Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination | HENG ET AL. | Examiner | John B. Vigushin | 2841 | Page 1 of 1 | U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-2003/0089998 A1	05-2003	Chan et al.	257/777
	В	US-2002/0167079 A1	11-2002	Pu et al.	257/685
	С	US-2001/0000013 A1	03-2001	Lin, Mou-Shiung	257/777
	D	US-6,555,917 B1	04-2003	Heo, Young Wook	257/777
	E	US-6,522,015 B1	02-2003	Glenn et al.	257/777
	F	US-6,420,787 B1	07-2002	Kobayashi et al.	257/777
	G	US-6,413,797 B2	07-2002	Oka et al.	438/108
	Н	US-			
	1	US-			
	J	US-			
	к	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	ď					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	U						
	٧						
	w						
	x						

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.